Final Program 4-11-14 JWS.xlsx 4/11/2014

		PAPER TITLE	AUTHOR	Company		
Session ID / Paper	Time	Technical Sessions	Session Chair	Session Co-Chair		
	AM	Counterfeit- Prevention & Mitigation Strategies	Aaron DerMardersosian	S. Ali Lilani		
Α		Seminar Room An Update on the Authentication Platform DLA has Selected as Part of	aaron_dermarderosian_jr@raytheon.com	Sultan.Lilani@integra-tech.com		
1	8:30-8:55	their Counterfeit Prevention Effort	Janice Meraglia	Applied DNA Sciences		
2	8:55-9:20	Defense Electronic - Trends	Tina Barcley	TAS Consulting		
3	9:20-9:45	Counterfeit Analysis Supply Chain Case Studies - Counterfeit Detection & Quality Control Non Conformance Issues	Aaron DerMardersosian, Jr.	Raytheon Company		
	BREAK					
4	10:15-10:40	Ceramic Taggants for Authentication or Provenance Marking of Electronic Components	Dr. Arthur Jonath, Jr.	Arthur Jonath Associates		
5	10:40-11:05	Save Time and Money by Carefully Selecting Plastic Packaged Integrated Circuits	S. Ali Lilani	Integra Techchnologies		
	АМ	RF and Microwave - Innovations and Emerging Technologies - Part I	Tom Terlizzi	Larry Hawkins		
В		Colonial Room	terlizzi@gmsystems.com	Larry.Hawkins@analog.com		
1	8:30-8:55	The Current State of Integration in IC's	Larry Hawkins	Analog Devices Inc.		
2	8:55-9:20	Packaging Technologies Behind GaN Power Transistors for High Power S-Band Radar Applications	Chris Hermanson	Cree, Inc.		
3	9:20-9:45	High Temperature Cofired Ceramic (HTCC) Package Design and Applications	Ken McGillivray	HCC Electronic Packaging - (Aegis Ametek)		
	BREAK					
4	10:15-10:40	Optimization of Tin Vapor Deposition Process on Tungsten-Copper Substrate	Sanchayan Dutta	Santier		
5	10:40-11:05	High Reliability Designs and Manufacturing of RF Components and Assemblies	Chandra Gupta	Hittite Microwave Corp.		
6	11:05-11:30	GaN Doherty Amplifiers for Commercial and Military Applications	Tom Kelly	NXP Semiconductors		
	AM	Bumped Die Attach	Jim McLenaghan	Dan Baldwin		
С		Cotillion Room	ajm@creyr.net	dan.baldwin@engentaat.com		
1	8:30-8:55	Next Generation Assembly Structures using Copper Wire Bonding Interconnection	Dr. Dan Baldwin	Engent, Inc.		
2	8:55-9:20	Process Development for Ball Grid Array Attachment on DuPont™ Green Tape™ 9K7 LTCC	Allan Beikmohamadi	DuPont Microcircuit Materials		
3	9:20-9:45	Thermo-Sonic Flip Chip Methods on Copper or Solder Interconnect Structures	Tae Yi	Panasonic Factory Solutions Co., LTD		
	BREAK					
4	10:15-10:40	Reliability Issues in Flip Chip Design	Ed Dodd	DfR Solutions		
5	10:40-11:05	Using Solid State Micro-Batteries in Flip-Chip Applications	Jeff Sather	Cymbet Corp		
6	11:05-11:30	Selecting Stencil Technologies to Optimize Print Performance	Chrys Shea	Shea Engineering		
	AM	NANO and MEMS	Dr. Alan Rae	Matt Apanius		
D		Directors Room	arae@nanomic.org	matt@smartmicrosystems.com		
1	8:30-8:55	From Automotive Crash Sensing to Consumer Electronics and Beyond	Rob O'Reilly	MEMS Sensor and Technology Group, Analog Devices, Inc.		
2	8:55-9:20	Advances in Thin, 3D and MEMS Die Bond Strength Testing	Bob Sykes	XYZTECbv		
3	9:20-9:45	Nanomanufacturing and Electronics	Alan Rae	NanoMaterials Innovation Center, LLC		
	BREAK					
4	10:15-10:40	Optical Leak Testing of MEMS Devices	Chris Aubertin	Norcom Systems Inc.		
5	10:40-11:05	Alternative Miniature Vibration Sensor Technology	Dr. Atul Pradhan	Micatu, Inc.		
Keynote Lunch Speaker						
Keynote Lunch Speaker Postoring Vision with Subretinal Implants Dr. Time Lebeld Poting Implant AG						
		Restoring Vision with Subretinal Implants	Dr. Timo Lebold	Retina Implant AG		

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	PM	Wire Bonding & Advanced Interconnections (Cu)	Bill Boyce	
E		Seminar Room	wboyce@sensata.com	
1	1:00-1:25	Design & Process Considerations to Avoid Resonance Induced Heel Cracks during an Ultrasonic Wire Bond Process	James Card	Sensata Technologies
2	1:25-1:50	Aluminum and Copper Wire Bonding to ENIG and ENEPIG	George Milad	Uyemura International Corp.
3	1:50-2:15	Configurations for Robust Gold Stitch-to-Substrate Wire Bond Attachment – Part 2	Ashley Hlavacik	Desich SMART Center
4	2:15-2:40	Heavy Copper Wedge Bonding in Power Electronics	Dr. Michael Broekelmann	Hesse Mechatronics, Inc.
5	2:40-3:05	Reworkable Interconnects using Alternative Materials	Dr Michael C. Hamilton	Auburn University
	PM	RF and Microwave - Innovations and Emerging Technologies - Part II	Tom Terlizzi	Larry Hawkins
F1		Colonial Room	terlizzi@gmsystems.com	Larry.Hawkins@analog.com
1	1:00-1:25	Non-Hermetic Packaging of RF Microwave Modules	Matt Gruber	Lockheed Martin
2	1:25-1:50	A High Performance Single Component Conductive Epoxy for Inter- Connecting Silicon Stacked Die Layers - And a New Development for Globtop	Samuel Forman	Microcoat Techologies
	PM	Novel Technologies	Dmitry Marchenko	
F2		Colonial Room	dmitry.marchenko@microsemi.com	
3	1:50-2:15	Development of Low Temperature Sintered Nano Silver Pastes Using MO Technology and Resin Reinforcing Technology	Tony Tuscigno	NAMICS Technologies
4	2:15-2:40	Design and Fabrication of a Highly Integrated Silicon Detector for the STAR Experiment at Brookhaven National Laboratories	Benjamin Buck	MIT/Brookhaven Laboratories
5	2:40-3:05	Packaging and Ceramic Feedthroughs for the Boston Retinal Prosthesis	Tom Salzer	Hermetric Inc.
	PM	Technologies and Methods for 2.5/3D Packaging	Ken Aruajo	Maria Durham
G	LIAI	Cotillion Room	araujo@namics-usa.com	mdurham@indium.com
1	1:00-1:25	Pre-Applied Materials for 2.5/3D Technology	Tony Tuscigno	NAMICS Technologies
2	1:25-1:50	Progress in Fabrication and Test of Glass Interposer Substrates	Aric Shorey	Corning, Inc.
3	1:50-2:15	Comparison of Measured and Modeled Lithographic Process Capabilities for 2.5D and 3D Applications Using a Step and Repeat Camera	James Webb	Rudolph Technologies, Inc.
4	2:15-2:40	Recent Advances in Die Attach Film and Temporary Wafer Protection	Frederick Lo	Al Technology Inc
5	2:40-3:05	Evaluating Underfill Material for 3D Integration of High Density Heterogeneous Sensor Arrays	Chris Gregory	RTI International
	All Day	Poster Session	Dr. Wei Han	Dy Dita Mahantu
	All Day			Dr. Rita Mohanty
Н		Federal Room / Registration Area The Effect of Current Density on the Grain Size and Surface Morphology	weihan.vivian@gmail.com	ritam1010@hotmail.com Department of Chemical Engineering
1		of Electrodeposited Pt Nanowires Low Temperature Soldering Using Tin/Indium (Sn/In) Lead-free	Dajiang Ruan	University of Massachusetts Lowell Department of Chemical Engineering
2		Nanosolders	Yang Shu	University of Massachusetts Lowell
3		Microfluidic Synthesis of Lead-free Nanosolder Particles	Zhiyang Li	Department of Chemical Engineering University of Massachusetts Lowell
4		PCA Environmental Compliance and Verification Tools	Scott Mazur	Benchmark Electronics-NH
5		Hydrogen for Small Scale Semiconductor Fabrication and Packaging	Dave Wolff	Proton On Site
6		Criteria for Selecting a Solder Paste and Troubleshooting Common Challenges	Derrick Herron	Indium Corporation, NY
7		Packaging of GaAs Chips for Use in RF MCM Products	Caroline K. Bjune	Draper Laboratory
8		Additive Manufacturing for Biomedical Applications	Jianyu Liang	Worchester Polytechnic Institute
9		Cold Spray for Enabling Innovaitons in Electronics	Jianyu Liang	Worchester Polytechnic Institute